FEI Nova 200 Dual-Beam SEM/FIB

Capabilities:
- FEG scanning electron microscope
- Ion column with Ga liquid ion source for milling
- GIS for Pt deposition
- Kleindiek nanomanipulator for specimen lift-out
- Oxford Inca EDS system
- AutoTEM, AutoFIB, and slice and view automation software

Current Research Activities:
- Support instrument for atom probe and TEM specimen preparation
- 3D reconstruction of microstructural features

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Fabricating AP specimen from TEM foil